

**Supplementary Information AM-11-047 for**

**Structural studies of NH<sub>4</sub>-exchanged natrolites at ambient conditions  
and high-temperature**

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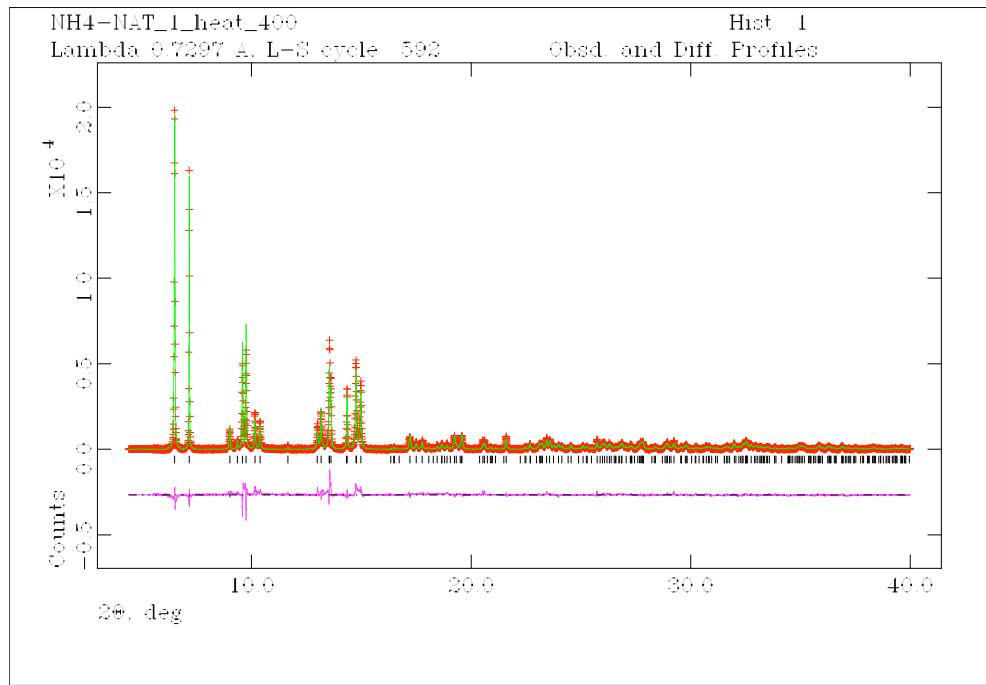
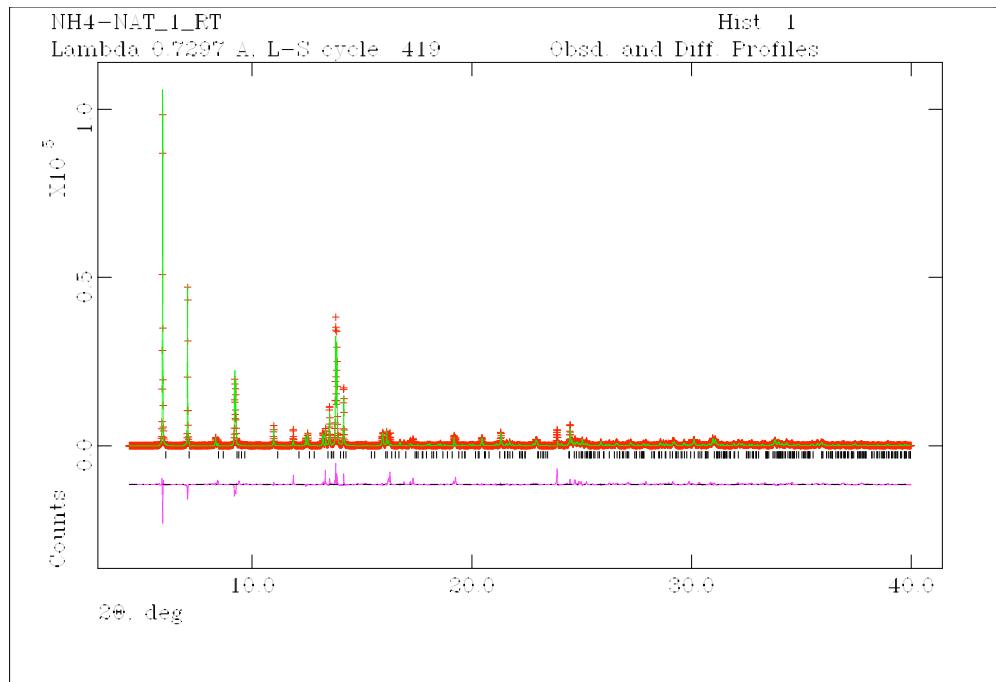
Supplementary Table 1. EDS chemical composition of the fully and partially NH<sub>4</sub>-exchanged natrolites.<sup>a</sup>

Fully NH <sub>4</sub> -exchanged natrolite					
Elements		N	K	Al	Si
Atomic percent (%)	1	9.77	0.00	9.47	12.88
	2	9.72	0.00	9.33	13.05
	3	9.12	0.00	10.30	14.10
	4	9.46	0.00	9.50	13.21
	5	10.00	0.00	9.73	13.57
	6	10.62	0.00	9.50	13.02
Unit cell composition		$(\text{NH}_4)_{16.24}\text{Al}_{16}\text{Si}_{24}\text{O}_{80} \cdot x\text{H}_2\text{O}$			
Partially NH <sub>4</sub> -exchanged natrolite					
Elements		N	K	Al	Si
Atomic percent (%)	1	4.30	6.76	10.84	15.90
	2	5.17	6.17	10.34	15.60
	3	2.04	6.64	11.41	18.12
	4	2.46	6.73	11.04	17.89
	5	3.06	6.59	10.42	17.79
	6	3.44	7.40	10.94	16.50
	7	2.33	6.95	11.16	17.85
Unit cell composition		$(\text{NH}_4)_{4.78}\text{K}_{9.93}\text{Al}_{16}\text{Si}_{24}\text{O}_{80} \cdot x\text{H}_2\text{O}$			
Atomic ratio of N <sup>+</sup> : K <sup>+</sup>		0.325 : 0.675			

<sup>a</sup>Values are normalized based on 16 aluminum atoms per unit cell.



Supplementary Figure 1. Rietveld refinement fits of the structural models of the fully NH<sub>4</sub>-exchanged natrolite at RT (upper) and at 400°C (lower) using synchrotron X-ray powder diffraction data. Points shown represent the observed data. The continuous lines through the sets of points are the calculated profiles from the structure refinements summarized in Tables 1-2. The sets of tic marks below the data indicate the positions of the allowed reflections. The lower curves represent the differences between observed and calculated profiles ( $I_{\text{obs}} - I_{\text{calc}}$ ) plotted on the same scale as the observed data.



Supplementary Figure 2. Rietveld refinement fits of the structural models of the partially NH<sub>4</sub>-exchanged natrolite at RT (upper), at 400°C (middle), and after one week of exposure to atmospheric conditions (lower) using synchrotron X-ray powder diffraction data. Points shown represent the observed data. The continuous lines through the sets of points are the calculated profiles from the structure refinements summarized in Tables 1-2. The sets of tic marks below the data indicate the positions of the allowed reflections. In the case of the fit to the 400°C data, the K-rich phase is included as a minor secondary phase. The lower curves represent the differences between observed and calculated profiles ( $I_{\text{obs}} - I_{\text{calc}}$ ) plotted on the same scale as the observed data.

